

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	7034	chuck and wafer and plasma	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 13:35
S2	920	(arc or spike) and S1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/11 17:45
S3	775	(etch or etching) and S2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/11 17:54
S4	170	signal and detector and S3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/11 17:53
S5	640	susceptor and (arc or spike) and semiconductor	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/11 17:54
S6	412	(etch or etching) and S5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/11 17:54
S7	17	(dechucking or de-chucking) and S6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/11 17:55
S8	11	("20020043527"   "20020043530"   "20020055021"   "20030015521"   "4613455"   "5154863"   "5350720"   "6465763"   "6475606"   "6507006"   "6677557").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/06/11 17:57

S9	2	(arc adj detecting or arc adj detection) and (chuck or electro adj static adj chuck or esd adj chuck)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 11:47
S10	196	rha.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:20
S11	25	circuit and S10	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:21
S12	0	john adj rha	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:22
S13	34930	adams.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:22
S14	721	wafer and S13	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:22
S15	399	circuit and S14	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:22
S16	148	(detect or detecting or detection) and S15	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:23

S17	26	(arc or arcing) and S16	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:23
S18	12	(etch or etching) and S17	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:23
S19	60	vrf near4 circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:26
S20	3	gate adj input and S19	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:38
S21	0	esc same vrf and signal and circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:38
S22	0	(esc same vrf) and signal and circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:38
S23	2	esc and vrf and signal and circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 12:59
S24	5	comdel.as.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 13:01

S25	26	"5175472".uref.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 13:05
S26	1	arcing adj suppression adj circuit or arching adj suppress adj circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 13:07
S27	27	spike adj suppression adj circuit or spike adj suppress adj circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 13:07
S28	0	data adj aquisition and wafer and etch and spike	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 13:18
S29	669	over adj voltage adj protection adj circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 13:35
S30	5	a/d and d/a and S29	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/22 13:36